

Laboratory **UL India Lab, UL India Pvt. Ltd., Laboratory Building, Kalyani Platina Campus, Sy. No. 129/4, EPIP Zone, Phase-II, Whitefield, Bangalore, Karnataka**
Location 1: Laboratory Building, Kalyani Platina Campus, Sy. No. 129/4, EPIP Zone, Phase-II, Whitefield, Bangalore, Karnataka
Location 2: OAK Building, Kalyani Platina Campus, Sy. No 129/4, EPIP Zone, Phase-II , Whitefield, Bangalore, Karnataka

Accreditation Standard **ISO/IEC 17025: 2005**

Discipline **Electronics Testing** **Issue Date** **05.08.2016**

Certificate Number **T-1432** **Valid Until** **04.08.2018**

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
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LOCATION: 1

I. ENVIRONMENTAL TESTING

1.	Environmental Testing of Electronics & Electrical Items	Low Temperature (Cold) Test	QM333 Issue. 2: 1998	25 °C to (-)65 °C 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH
		High Temperature (Dry) Heat	QM333 Issue. 2: 1998	30 °C to 150 °C 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH
		Rapid Temperature Cycle (2 chamber method)	QM333 Issue. 2: 1998	(-)65°C to 150 °C 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH

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	Environmental Testing of Electronics & Electrical Items	Water Immersion Test	QM333 Issue. 2: 1998	15 °C to 35 °C
		Corrosion (Salt)	QM333 Issue. 2: 1998	35 °C, 95 % RH
		Drop Test	QM333 Issue. 2: 1998	10 mm to 2000 mm, 45°
		Toppling Test	QM333 Issue. 2: 1998	10 mm to 2000 mm
		Fall Test	QM333 Issue. 2: 1998	10 mm to 2000 mm
		Cold Test	EN/IEC 60068-2-1: 2007	25 °C to (-)65 °C
		Dry Heat	EN/IEC 60068-2-2: 2007	30 °C to 150 °C
			1000 mmW x 800 mmD x 1000 mmH	
			3048 mmW x 3658 mmD x 2388 mmH	
			1829 mmW x 1829 mmD x 2388 mmH	
			1000 mmW x 800 mmD x 1000 mmH	
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	Environmental Testing of Electronics & Electrical Items	Salt Mist Test	IEC 60068-2-11, (3 rd Edition): 1981	25 °C to 35 °C, 95 %Rh 2160 mmW x 980 mm D x 1320 mmH
		Change of Temperature (Test Na) (2 chamber method)	IEC 60068-2-14 (6 th Edition): 2009	(-)65°C to 150°C 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH
		Damp heat, cyclic (Test Db)	IEC 60068-2-30,(3 rd Edition): 2005-08	22 °C to 55 °C, 35 % to 95 % Rh 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH

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	Environmental Testing of Electronics & Electrical Items	Salt Mist, Cyclic, Test Kb (sodium chloride solution)	IEC 60068-2-52, (2 nd Edition): 1996	25 °C to 35 °C, 95 %Rh 2160 mmW x 980 mmD x 1320 mmH
		Water – IPX1 to IP X7 Degrees of Protection): provided by enclosures	IEC 60529: 2013-08, (Edition 2.2) 1+ Corr. 3	IPX1 to IP X7 Qualitative
		Dust- IP 1 x to IP 6 x Degrees of Protection): provided by enclosures	IEC 60529: 2013-08, (Edition 2.2) 1+Corr. 3	IP 1 x to IP 6 x Qualitative
		Damp Heat, steady state	IEC 60068-2-78 (2 nd Edition): 2012-10	30 °C to 40 °C, 35 % to 95 % Rh 1000 mmW x 800 mmD x 1000 mmH 3048 mmW x 3658 mmD x 2388 mmH 1829 mmW x 1829 mmD x 2388 mmH

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II. INFORMATION TECHNOLOGY EQUIPMENTS

1. Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Input Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 1.6.2)	1.5 V to 300 VAC/DC 1 mA to 20 A AC/DC
	Thermal requirement	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.5.1)	20 °C to 400 °C
	Overload of operator accessible Parts	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.3.7)	1 W to 330 W(max) 0.1 s to 1 hr
	Humidity conditioning	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.9.1)	93 % to 95 % RH 20 °C to 100 °C Qualitative
	Electric strength Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.2.2)	50 V to 10 kV AC/DC 1 s to 900 s
	Touch current Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.1)	0.1 mA to 5 mA
	Abnormal operation Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.3.1)	25 °C to 400 °C Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Capacitance discharge Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.1.1.7)	0.1 V to 800 V Peak / DC 5 s
		Limited power source measurement Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.5)	1 W to 330 W(max) 0.1 s to 1 hr
		Working voltage determination	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.10.2)	1 V to 1000 V rms/V DC
		Protective bonding Test II	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.6.3.4)	0.01 Ω to 0.3 Ω 5 s to 600 s A to 60 A
		Limited current circuit measurements	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.4.1)	0.1 mA to 5 mA
		Limitation of touch current to a telecommunication and cable distribution system	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.1.8.1)	0.1 mA to 5 mA
		Requirement of separation between telecommunication network from earth	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 6.1.2)	1 V to 2 kV AC/DC 1-900 s
		Steady force Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.1)	0.1 s to 1 hr 1 N to 900 N Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Impact Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.5)	1 mm to 3000 mm 500 g
		Strain relief Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 3.2.6)	0.1 s to 1 hr to 60 N Qualitative
		Cord guard Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 3.2.8)	5 ° to 90 ° 15.5 mm to 25 mm
		Hazardous moving Parts Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.4.2)	Test finger - Figure 2A Qualitative
		Stability Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.1)	5 ° to 60 ° Qualitative
		Durability of marking Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 1.7.11)	Qualitative (Visual inspection)
		Stress relief Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.7)	25°C to 150 °C Qualitative
		Drop Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.6)	1 mm to 3000 mm Qualitative

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III. AUDIO/ VIDEO COMPONENTS AND PRODUCTS

1.	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Humidity treatment	EN/IEC 60065: 2005, Clause. 10.2 IS 616: 2010, Clause. 10.2	28 °C to 50 °C 90 % to 95 % RH Qualitative
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IV. ELECTRO-MEDICAL EQUIPMENTS

1.	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Document Review	IEC 60601-1-6 (3 rd Edition): 2010	Qualitative
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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Environmental Test conditions of transport and storage	IEC 60601-1-11 (1 st Edition): 2010	(-)25 °C to (+)70 °C
			Sub-Clause. 4.2.1	90 % to 95 % RH
		Environmental Test operation condition	IEC 60601-1-11 (1 st Edition): 2010	(+)5 °C to (+)40 °C
			Sub-Clause. 4.2.2	15 % to 95 %
		Harmful Ingress of Liquids Test	IEC 60601-1-11 (1 st Edition): 2010	IP22
			Sub-Clause. 8.3	1 N to 30 N 150 Tilt Flow rate 3 mm/min 2.5 min IP21 1 to 30 N Enclosures on turn table Flow rate 1 mm/min 10 min
		Free Fall Test	IEC 60601-1-11 (1 st Edition): 2010 Sub Clause: 10.1.3d	1 m 2 falls from specified altitude. for mass ≤ 1 kg, 0.25 m for mass > 1 kg and ≤ 10 kg, 0.1 m for mass > 10 kg and ≤ 50 kg, 0.05 m for mass > 50 kg, 0.01 m.

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2.	Ambulatory electrocardiographic systems	Drop Impact Test	IEC 60601-2-47 (2 nd Edition): 2012 Sub-Clause. 201.15.3.4.2	10 mm to 2000 mm, 45 °
Linearity and dynamic range		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.101	(±)300 mV DC, 0.5 mV to 5mV, 0.4 Hz to 40 Hz	
Input Impedance		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.102	1 mV to 300 mV DC 0.67 Hz to 40 Hz	
Common Mode Rejection		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.103	1 mm to 300 mm, 50 Hz to 60 Hz	
Gain Accuracy		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.104	1 l/min to 350 l/min	
Multichannel Crosstalk		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.107	0.5 mV to 2.5 mV, 0.1 mm to 1 mm 1 Hz to 30 Hz	
Frequency Response		IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.108	1 Hz to 40 Hz, 0.1 mV to 1 mV, 1 mm to 300 mm	

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	Ambulatory electrocardiographic systems	Function In the Presence of Pacemaker Pulses	IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.109	2 mV to 500 mV, 2 ms
		Timing Accuracy	IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.110	Qualitative
		GAIN Settings and Switching	IEC 60601-2-47 (2 nd Edition): 2012 Sub Clause. 201.12.4.4.111	1 mm to 30 mm
3.	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Power input Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 7.1)	1 mA to 20 A max 2000 W
		Voltage limitation Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 15)	0.1 V to 800 V peak
		Earthing and potential equalization Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 18 f)	0.001 Ω to 0.3 Ω , 1 s to 600 s

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Dielectric voltage withstand Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 20.4)	10 V to 10 kV AC/DC 10 s to 900 s 1 mA to 100 mA
		Leakage current Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 19)	0.1 mV to 1000 mV
		Temperature Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 42)	17 °C to 400 °C
		Humidity conditioning Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 44.5)	93 %RH to 95 % RH Minus: 20 °C to 100 °C
		Abnormal operations and fault conditions Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 52)	17 °C to 400 °C

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Marking durability Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 6.1)	0.1 s to 60 s
		Enclosure mechanical strength	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 21a,b)	0.2 J to 1.0 J 1 N to 200 N
		Stability and transportability Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 24)	1 ° to 15 °
		Ball pressure Test	UL 60601-1 (1 st Edition): 2003 Revision 2006 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995 (Clause. 59.2)	17 °C to 150 °C 0.01 mm to 10 mm
		Legibility of Markings	IEC 60601-1 (3 rd Edition): 2005 Amd 1: 2012, Clause. 7.1.2 IS 13450 (Part 1): 2008, Clause. 7.1.2	100 lx to 1500 lx

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Voltage mismatch	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 7.2.6 IS 13450 (Part 1): 2008, Clause. 7.2.6	1 V to 440 VAC 0.5 V to 24 VDC
		Shorting one MOP	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.1b IS 13450 (Part 1): 2008, Clause. 8.1b	Qualitative
		Incorrect Polarity	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.2.2 IS 13450 (Part 1): 2008, Clause. 8.2.2	Qualitative
		Patient Lead Connection	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.5.2.3 IS 13450 (Part 1): 2008, Clause. 8.5.2.3	0.2 mm to 300 mm 0.06 kV to 10 kV 0.02 - 50N
		Working Voltage Measurement	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.5.4 IS 13450 (Part 1): 2008, Clause. 8.5.4	20 V to 1000 Vrms/VDC

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	Applied Electromagnetic radiation equipment;	Thermal Cycling for spaces filled with insulating material,	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.9.5 IS 13450 (Part 1): 2008, Clause. 8.9.5	20 °C to 100 °C
	Applied Current/Energy Equipment;	Temperature and Overload Control Device	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.4.2.1 IS 13450 (Part 1): 2008, Clause. 15.4.2.1	10 to 200 Cycle
	Ultrasound Equipment;	Reverse Battery Connection/Overcharging by inspection	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.4.3 IS 13450 (Part 1): 2008, Clause. 15.4.3	Qualitative
	Cardio, Vascular and Pulmonary Equipment;	Transformer Short Circuit	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15. 5.1.2 IS 13450 (Part 1): 2008, Clause. 15. 5.1.2	1 °C to 400 °C 0.1 kV to 10 kV AC/DC
	General Medical Equipment;	Transformer Overload	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.5.1.3 IS 13450 (Part 1): 2008, Clause. 15.5.1.3	1 °C to 400 °C 0.1 kV to 10 kV AC/DC
	Patient-monitoring Equipment	Transformer Dielectric Voltage Withstand	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.5.2 IS 13450 (Part 1): 2008, Clause. 15.5.2	0.1 kV to 10 kV AC

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	ME System Leakage Current	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 16.6.1 IS 13450 (Part 1): 2008, Clause. 16.6.1	0.1 mA to 1.000 mA
		Limitation of Voltage, Current or Power	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.4.2 IS 13450 (Part 1): 2008, Clause. 8.4.2	0.1 V to 60 V 0.1 V to 800 VA 1 mA to 20 A max
		Defib-Proof Applied Parts	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.5.5 IS 13450 (Part 1): 2008	1 kV to 5 kV AC/DC
		Defib-Proof Applied Parts, Energy Reduction	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.5.5.2 IS 13450 (Part 1): 2008, Clause. 8.5.5.2	1 kV to 5 kV AC/DC
		Stability and transportability Test	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.2 IS 13450 (Part 1): 2008	1 ° to 15 ° 0.36 N to 800N
		Cord Anchorage	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.11.3.5 IS 13450 (Part 1): 2008, Clause. 8.11.3.5	0.36 N to 100 N 0.139 mm to 300 mm 0.03 Nm to 1 Nm

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Program Manager

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Cord Bending	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.11.3.6 IS 13450 (Part 1): 2008, Clause. 8.11.3.6	0.13 mm to 300 mm, 0.2 kg to 5 kg 1 ° to 45 °
		Measurement of Gaps(Trapping Zones)	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.2.2.2 IS 13450 (Part 1): 2008, Clause. 9.2.2.2	0.13 mm to 300 mm
		Mobile Equipment Force for Propulsion	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.2.4.2 IS 13450 (Part 1): 2008	0.36 N to 500 N 0.79 s to 600 s 1 m to 3 m 1 mm to 4 mm
		Mobile Equipment Over a Threshold	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.2.4.3 IS 13450 (Part 1): 2008, Clause. 9.4.2.4.3	5 s to 600 s 1 mm to 80 mm
		Instability from Unwanted Lateral Movement (Including Sliding),	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.3.1 IS 13450 (Part 1): 2008, Clause. 9.4.3.1	1 ° to 10 ° 1 mm to 300 mm

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Instability Excluding Transport	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.3.2 IS 13450 (Part 1): 2008, Clause. 9.4.3.2	1 ° to 10 ° 1 mm to 300 mm 1 N to 150 N
		Handle Loading	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.4.4 IS 13450 (Part 1): 2008, Clause. 9.4.4	5 s to 600 s 1 N to 500 N 1 kg to 100 kg
		Mechanical Strength-Patient Support System	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.8.3.1 IS 13450 (Part 1): 2008, Clause. 9.8.3.1	1 kg to 270 kg
		Mechanical Strength – Foot Rest	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.8.3.2 IS 13450 (Part 1): 2008, Clause. 9.8.3.2	1 kg to 135 kg
		Mechanical Strength – Dynamic Forces	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.8.3.3 IS 13450 (Part 1): 2008, Clause. 9.8.3.3	1 kg to 270 kg

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Suspension system w/Safety Devices Loading	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.8.4 IS 13450 (Part 1): 2008, Clause. 9.8.4	1 kg to 100 kg
		Harmful Ingress	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 11.6.5 IS 13450 (Part 1): 2008, Clause. 11.6.5	1 mm to 300 mm, 0.1 s to 1 hr
		Cleaning and Disinfection of ME Equipment's and ME Systems	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 11.6.6 IS 13450 (Part 1): 2008, Clause. 11.6.6	0.1 kV to 10 kV AC/DC
		Actuating Parts of Control of ME Equipment	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.4.6 IS 13450 (Part 1): 2008, Clause. 15.4.6	1 N to 100 N 0.2 Nm to 6 Nm
		Cord – Connected Foot Operated Control Devices	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 15.4.7.1 IS 13450 (Part 1): 2008, Clause. 15.4.7.1	1 N to 1350 N

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Short Circuiting in Lieu of Spacing	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 8.9.2 IS 13450 (Part 1): 2008, 8.9.2	Qualitative (Visual Inspection)
		Overflow	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 11.6.2 IS 13450 (Part 1): 2008, Clause. 11.6.2	1 ° to 10 ° 1 V to 10 V 1 kV to 10 kVAC 5 s to 600 s
		Spillage	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 11.6.3 IS 13450 (Part 1): 2008, Clause. 11.6.3	1 V to 10 V 1 kV to 10 kVAC 1 ml to 200 ml.
		Leakage	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 11.6.4 IS 13450 (Part 1): 2008, Clause. 11.6.4	1 ml to 200 ml
		Acoustic Energy Measurement	IEC 60601-1 (3 rd Edition): 2005 Amd. 1: 2012, Clause. 9.6.2.1 IS 13450 (Part 1): 2008, Clause. 9.6.2.1	2 dB to 100 dB
		Power input Test	IEC 60601-1 (3 rd Edition): 2005 IS 13450 (Part 1): 1994 IS 13450 (Part 1): 2008 (Clause. 4.11)	1 mA to 20 A max 10 s to 900 s

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Voltage or Charge Limitation	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 8.4.3)	0.1 V to 800 V peak
		Impedance and Current Carrying Capability	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 8.6.4a)	0.001 Ω to 0.3 Ω , 1 s to 600 s
		Dielectric voltage withstand Test	IEC 60601-1 (3 rd Edition): 2005	10 V to 10 kV AC/DC
			IS13450 (Part 1): 2008 (Clause. 8.8)	10 s to 900 s
		Leakage current Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 8.7)	0.1 mA to 1000 mA
		Temperature Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 11)	17 °C to 400 °C
		Marking durability Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 7.1.3)	0.1 s to 60 s
		Humidity conditioning Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 5.7)	93 %RH to 95 % RH 20 °C to 100 °C

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Interruption power supply Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 11.8)	Qualitative (Visual Inspection)
		Abnormal operations and fault conditions Test	IEC 60601-1 (3 rd Edition): 2005 IS13450 (Part 1): 2008 (Clause. 13)	17 °C to 400 °C
		Enclosure mechanical strength	IEC 60601-1 (3 rd Edition): 2005	10 g to 80 kgf
			IS 13450 (Part 1): 2008 (Clause. 15.3)	0.1 s to 1 hr
		Instability Hazards	IEC 60601-1 (3 rd Edition): 2005 IS 13450 (Part 1): 2008 (Clause. 9.4.3)	0.1 ° to 15 °
		Ball pressure Test	IEC 60601-1 (3 rd Edition): 2005 IS 13450 (Part 1): 2008 (Clause. 8.8.4.1)	0.1 °C to 150 °C 0.01 mm to 10 mm
	Defibrillation-Proof Applied Parts	IS 13450 (Part 1): 1994, Clause. 17 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 17 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 17	1 kV to 5 kV AC/DC	

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Handle Loading Test	IS 13450 (Part 1): 1994, Clause. 21 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21 UL 60601-1 (1st Edition): 2003 Revision 2006, Clause. 21	5 s to 600 s 1 N to 500 N 1 kg to 100 kg
		Mechanical Strength - Patient Support System	IS13450 (Part 1): 1994, Clause. 21.3 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21.3 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 21.3	1 kg to 270 kg (min)
		Mechanical Strength - Foot Rests/Chairs	IS 13450 (Part 1): 1994, Clause. 21.3 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21.3 UL 60601-1 (1st Edition): 2003 Revision 2006, Clause. 21.3	1 kg to 135 kg (min) 5 s to 600 s

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Drop Impact Test	IS 13450 (Part 1): 1994, Clause. 21.5 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21.5 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 21.5	1 m
		Rough Handling – Drop Test	IS13450 (Part 1): 1994, Clause. 21.6 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21.6 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 21.6	1 mm to 50 mm
		Rough Handling – Roll Off Step Test	IS 13450 (Part 1): 1994, Clause. 21.6 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 21.6 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 21.6	5 s to 600 s 1 m to 3 m 1 mm to 4 mm

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	Applied Electromagnetic radiation equipment;	Suspension System With Safety Devices Loading Test	IS 13450 (Part 1): 1994, Clause. 28.3 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 28.3 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 28.3	1 kg to 100 kg
	Applied Current/Energy Equipment;			
	Ultrasound Equipment;			
	Cardio, Vascular and Pulmonary Equipment;	Suspension Systems without Safety Device Loading Test	IS 13450 (Part 1): 1994, Clause. 28.4 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 28.4 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 28.4	1 kg to 100 kg
	General Medical Equipment;			
	Patient-monitoring Equipment			
		Harmful Ingress of Liquids Test	IS13450 (Part 1): 1994, Clause. 44.6 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 44.6 UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 44.6	(0.1 kg to 7 kg)/cm ²

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Overflow, Spillage, Leakage, Cleaning, Disinfection, Harmful Ingress Of Liquids,	IS13450 (Part 1): 1994, Clause. 44 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 44 UL 60601-1 (1st Edition): 2003 Revision 2006, Clause. 44	(0.1 kg to 7 kg)/ cm ²
		Actuating Parts of Controls	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 56.10 IS 13450 (Part 1): 1994, Clause. 56.10 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 56.10	1 N to 100 N 1 Nm to 6 Nm
		Cord Connected Foot Switch Test	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 56.11 IS13450 (Part 1): 1994, Clause. 56.11 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 56.11	1 kg to 135 kg (min) 5 s to 600 s

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Cord Anchorages,	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 57.4 IS 13450 (Part 1): 1994, Clause. 57.4 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 57.4	1 N to 100 N 1 mm to 300 mm 1 Nm to 0.35 Nm
		Cord Bending	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 57.4 IS 13450 (Part 1): 1994, Clause. 57.4 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 57.4	1 mm to 300 mm, 1 kg to 5 kg 1 ° to 45 °
		Transformer Overload and Short-Circuit Tests,	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 57.9.1 IS 13450 (Part 1) Clause. 57.9.1 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 57.9.1	1 °C ~ 400 °C 1 kV to 10 kV AC/DC

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	Applied Electromagnetic radiation equipment; Applied Current/Energy Equipment; Ultrasound Equipment; Cardio, Vascular and Pulmonary Equipment; General Medical Equipment; Patient-monitoring Equipment	Transformer Dielectric Voltage Withstand	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 57.9.4 IS 13450 (Part 1): 1994, Clause. 57.9.4 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 57.9.4	1 kV to 10 kV AC/DC
		Interruption of Power Supply	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 56.7 IS 13450 (Part 1): 1994, Clause. 49 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 49	1 s to 30 s
		Reversed Battery Connection by inspection	UL 60601-1 (1 st Edition): 2003 Revision 2006, Clause. 56.7 IS13450 (Part 1): 1994, Clause. 56.7 IEC 60601-1 (2 nd Edition): 1988 AM 1: 1991, AM 2: 1995, Clause. 56.7	1 V to 440 VAC 0.5 V to 24 VDC

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4.	Medical electrical beds	Instability excluding transport	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.4.2.2	3 N to 3000 N 1 mm to 50 mm
		Instability from horizontal and vertical forces	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.4.2.3	3 N to 1100 N 1 mm to 50 mm
		Force for propulsion	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.4.2.4.2	3 N to 500 N
		Movement over a threshold	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.4.2.4.3	1 mm to 100 mm 0.1 m/s to 0.8 m/s
		Instability in transport	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.4.3.1	1 mm to 100 mm 1 ° to 10 °
		Audible acoustic energy	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.6.2.1	2 dB to 100 dB
		Static forces due to loading from persons	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.8.3.2	3 N to 4000 N
		Ingress of water	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.11.6.5.101	1 mm to 300 mm, 0.1 s to 1 hr

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	Medical electrical beds	Rough handling Test	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.15.3.5	0.4 m/s
		Limitation of movement	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.15.4.6.2	1 ° to 90 °
		Mechanical strength	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause 201.15.4.7.1	3 N to 1350 N
				5 s to 1 min
		Head/foot board assembly	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.15.4.101	5 s to 1 min
		The effect of impacts to the mattress support platform	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	20 kg
		The effect of loading on the edge of the – Mattress Support Platform	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	3 N to 750 N 1 mm to 300 mm
	Patient Entrapment in Non-Moving Parts	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.1.101	1 mm to 500 mm	

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	Medical electrical beds	Trapping Zone- Gaps	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.2.2.2 & 201.9.2.2.3	1 mm to 300 mm
		Continuous Activation:	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.2.2.5	Qualitative
		Interruption of the power supply/Supply Mains to me Equipment	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.11.8	1 s to 30s
		Range of Adjustment of Moveable Sections of the Mattress Support Platform	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	1 ° to 180 °
		Dimensions for Handles and Pedals	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	1 mm to 100 mm
		Operating Forces for Handles And Pedals	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	3 N to 300 N
		Combination of Medical Bed And Mobile Hoists ,	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	1 mm to 300 mm
		Combination Of Medical Bed And Mattress	IEC 60601-2-52 (1 st Edition): 2009 Corr. 1: 2010	1 mm to 20 mm

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5.	Pulse oximeter Equipment	Additional requirements for ingress of water or (Particulate matter into ME equipment or ME system)	DS/EN ISO 80601-2-61 (1 st Edition): 2011 Clause. 201.11.6.5.101	1 mm to 300 mm, 0.1 s to 1 hr
		Settings and data storage following short interruptions or automatic switchover	DS/EN ISO 80601-2-61 (1 st Edition): 2011 Clause. 201.11.8.101.2	5 s to 30 s
		Detection of pulse oximeter probe faults and probe cable extender faults	DS/EN ISO 80601-2-61 (1 st Edition): 2011 Clause. 201.13.101	Qualitative
		6.	Electrocardiographic monitoring Equipment	Defibrillation protection-common mode Test
Differential mode Test	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.8.5.5.1			1 kV to 5 kV AC/DC
Ingress of water or (Particulate matter into ME Equipment and ME System)	IEC 60601-2-27 (3 rd Edition): 2011 Clause. 201.11.6.5			1 mm to 300 mm, 0.1 s to 1 hr
Interruption): of the power supply / supply mains to ME Equipment	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.11.8			1 s to 30 s

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	Electrocardiographic monitoring Equipment	Accuracy of signal reproduction	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.1	1 mm to 24 mm, 0.1 mV to 2 mV, 1 Hz to 20 Hz
		Input dynamic range and differential offset voltage	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.2	(±)300 mV DC
		Input impedance	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.3	1 mV to 300 mV DC 0.67 Hz to 40 Hz
		Input Noise	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.4	1 min to 30 min, 1 mm to 10 mm
		Multichannel crosstalk	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.5	0.5 mV to 2.5 mV, 0.1 mm to 1 mm 1 Hz to 30 Hz
		GAIN control and stability	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.6	1 mm to 30 mm
		Sweep speed	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.7	1 mm to 30 mm

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	Electrocardiographic monitoring Equipment	Frequency and impulse response	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.8	0.67 Hz to 40 Hz, 0.1 mV to 1 mV, 1 mm to 300 mm
		Gain Indicator	IEC 60601-2-27 (3 rd Edition): 2011, Clause2 01.12.1.101.9	1 mm to 300 mm
		Common mode rejection	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.10	1 mm to 300 mm, 50 Hz to 60 Hz
		Baseline reset	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.11	0.1 V to 1 V, 10 Hz
		Pacemaker pulse display capability	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.12	2 mV to 700 mV
		Rejection of pacemaker pulses	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.13	0.1 ms to 2 ms 2 mV to 700 mV
		Synchronizing pulse for cardio version	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.14	1 ms to 35 ms
		Heart rate range, accuracy, and QRS detection range	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.15	1 l/min to 350 l/min
		Channel height and aspect ratio	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.16	0.1 Hz to 1 Hz, 0.1 mV to 1 mV, 1 mm to 300 mm

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	Electrocardiographic monitoring Equipment	Tall T-wave rejection capability	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.12.1.101.17	1 ms to 100 ms, 0.1 mV to 1 mV, 1 m to 300 mm
		Electrodes and Patient Cables	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 201.15.3.4.101	0.6 m to 1 m
		Time to alarm for heart rate alarm conditions	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 208.6.6.2.103	1 s to 20 s
		Technical alarm condition indicating inoperable ME equipment	IEC 60601-2-27 (3 rd Edition): 2011, Clause. 208.6.6.2.104	(-)5 V to (+)5 V 1 s to 20 s
7.	Electrically operated Hospital beds	Mechanical Strength – Bed System: Sub-Clause	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 21.3.101	3 N to 3000 N
		Mechanical Strength – Lifting Pole: Sub-Clause	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 21.3.102	0.1 min to 2 min 3 N to 1000 N
		Mechanical Strength – Wall Impact	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 21.6	1 m/s to 60 m/s 1 kg to 500 kg

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electrically operated Hospital beds	Mechanical Strength - End Panel Test Sub Clause	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 21.6.101	3 N to 450 N 1 mm ² to 700 mm ² 1 s to 35 s
		Mechanical Strength - Threshold Test Sub Clause	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 21.4, 21.6.102	1 mm to 100 mm 0.4 m/s
		Moving (Parts - Exposed Squeezing (Pinch) and Shearing Point Sub Clause.	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 22.2.101	1 mm to 200 mm
		Moving (Parts Bed Function Deactivation) Control Sub Clause.	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 22.2.102	Qualitative (Visual Inspection)
		Moving (Parts - Electric Powered Movement - Momentary Switches Sub Clause)	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 22.4.101	Qualitative (Visual Inspection)
		Surfaces Corners (Edges - Patient Entrapment)	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 23.101, Ref. 28.4.102	1 mm to 500 mm
		Stability In Normal Use - Lateral Stability, Longitudinal Stability Sub Clause.	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 24.3 AA	3 N to 3000 N

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	Electrically operated Hospital beds	Stability in Normal use Stability With Lifting Pole	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 24.3 bb	3 N to 1100 N
		Stability In Normal use Castor Locking	IEC 60601-2-38: 1996 + Amd. 1: 1999 , Clause. 24.4	1 ° to 10 ° 2 mm to 100 mm
		Vibration and Noise - Noise of Bed < 65db(A)	IEC 60601-2-38: 1996 + Amd. 1: 1999 , Clause26.101	2 dB to 100 dB
		Suspended Bed 2X SWL Masses	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 28.4.2 & 28.4.3	3 N to 4000 N 1 Min to 60 Min
		Suspended Masses Accessories 2X SWL	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 28.4.101	3 N to 4000 N 1 Min to 60 Min
		Suspended Masses Side Rail Strength	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 28.4.102/103	1 s to 30 s 1 to 10 Times
		Abnormal Operation & Fault Conditions Back Rest, Trendelenburg	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 52.5.102, 54.101	Qualitative (Visual Inspection)

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	Electrically operated Hospital beds	Components & General Assembly Head Panel Removal (No Tools) –	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 56.1.101	Qualitative (Visual Inspection)
		Components & General Assembly - Designated 'C' Angle > 90°	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 56.10(C)AA	1 ° to 180 °
		Components & General Assembly - Power Supply Cord Suspension	IEC 60601-2-38: 1996 + Amd. 1: 1999 Clause. 56.101 AA	1 m to 5 m
		Moving (Parts -Bed Function Deactivation Control)	IEC 60601-2-38: 1996 + Amd. 1: 1999, Clause. 22.2.102	Qualitative (Visual inspection)
8.	Multifunction patient monitor Equipment	Part Leakage Current	IEC 60601-2-49 (2 nd Edition): 2011-02 Clause. 201.8.7.1.101	0.1 μA to 1000 μA
		Ingress of water or (Particulate matter into Medical Equipment and Medical Systems	IEC 60601-2-49 (2 nd Edition): 2011-02 Clause. 201.11.6.5	Up to 7kg/cm ²
		Interruption): of the power supply / Supply Mains to Medical Equipment	IEC 60601-2-49 (2 nd Edition): 2011-02 Clause. 201.11.8	5 s to 30 s

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9.	Electro-cardiograph equipment	Defibrillation protection	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.8.5.5.1	1 kV to 5 kV AC/DC
		Requirements for amplitude measurements	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.1.101.2	0.5 mV to 10 mV
		Requirements for absolute interval and wave duration measurements	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.1.101.3.1	1 ms to 30 ms
		Requirements for interval measurements on biological ECG	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.1.101.3.2	1 ms to 30 ms
		Indication of inoperable Electrocardiograph	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.101	(-)5 V to (+)5 VDC 1 Hz to 10 Hz 1 mV to 5 mV
		Goldberger and Wilson Leads	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.102.3.2	0.5 mV to 10 mV
		Recovery time	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.102.4	1 mV to 300 mVDC, 1 min to 3 min
		Input impedance	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.103	1 mV to 100 mV (sine wave) 1 mV to 300 mV DC 0.67 Hz to 40 Hz

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	Electro-cardiograph equipment	Common Mode Rejection	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.105.1	1 V to 10 Vrms, 1 Hz to 60 Hz (±)300 mV DC
		Overload tolerance	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.105.2	0.02 V to 2V, 1 min to 5 min
		Noise Level	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.106.1	1 s to 10 s 0.01 mm to 1 mm
		Channel crosstalk	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.106.2	1 mV to 2.5 mV, 0.01 mm to 1 mm 1 Hz to 30 Hz
		Low frequency (impulse) response	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.107.1.1.2	0.03 mV to 0.3 mV
		Test with calibration ECGS	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.107.1.2	2.0 - 5mV
		Linearity and dynamic range	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.107.2	± 300mV DC, 0.5 mV to 5 mV, 0.4 -40Hz

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electro-cardiograph equipment	Recording speed	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.108.3.2	0.015- 100 mm
		Use with cardiac pacemakers	IEC 60601-2-25 (2 nd Edition): 2011 Clause. 201.12.4.109	2 mV to 500 mV, 0.1 to 2 ms
10.	X-Ray Equipment	Measurement of first HALF-VALUE LAYER	IEC 60601-1-3 (2 nd Edition): 2008 Amd.1: 2013 Clause. 7.1A IS 13450 (Part 1/ Sec 3): 2014 Clause. 7.1A	0.1 mmAl to 10 mmAl, 0.01 mGy to 10 Gy
		Measurement of the thickness of aluminium resulting in the same first Half-Value Layer in accordance with Table 3	IEC 60601-1-3 (2 nd Edition): 2008 Amd. 1: 2013 Clause. 7.5 IS 13450 (Part 1/ Sec 3): 2014 Clause. 7.5	0.1 mmAl to 10 mmAl
		Measurement of first Half-Value Layer Under Narrow Beam Conditions With X-Ray Equipment Operating At X-Ray Tube Voltages In Table 3 At Corr. Esponding Loading Factors In Normal Use	IEC 60601-1-3 (2 nd Edition): 2008 Amd. 1: 2013 Clause. 7.6 IS 13450 (Part 1/ Sec 3): 2014 Clause. 7.6	0.1 mmAl - 10 mmAl

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	X-Ray Equipment	Measurement of Focal Spot To Image Receptor Distance In Selected Configurations And Settings Of Equipment	IEC 60601-1-3 (2nd Edition): 2008 Amd. 1: 2013 Clause. 8.5.2 IS 13450 (Part 1/ Sec 3): 2014 Clause. 8.5.2	1 m to 3 m
		Measurement Of Leakage Radiation In The Loading State	IEC 60601-1-3 (2nd Edition): 2008 Amd. 1: 2013 Clause. 12.4 IS 13450 (Part 1/ Sec 3): 2014 Clause. 12.4	0.001 µGy/h to 1000 µGy/h
		Measurement Of Leakage Radiation When Not In The Loading State	IEC 60601-1-3 (2nd Edition): 2008 Amd. 1: 2013 Clause. 12.5 IS 13450 (Part 1/ Sec 3): 2014 Clause. 12.5	0.001 µGy/h to 100µGy/h
		Stray Radiation Of X-Ray Equipment	IEC 60601-1-3 (2nd Edition): 2008 Amd. 1: 2013 Clause. 13.6A IS 13450 (Part 1/ Sec 3): 2014 Clause. 13.6A	0.01 mGy to 1000 mGy
		Limits Of Air Kerma In One Hr	IEC 60601-1-3 (2nd Edition): 2008; Amd. 1: 2013 Clause. 13.6B IS 13450 (Part 1/ Sec 3): 2014 Clause. 13.6B	0.01 mGy to 1000 mGy

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
11.	Computed tomography Equipment	Limitation of voltage, current or energy	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 201.8.4	0.1 V to 800 V peak
		Leakage Currents And Patient Auxiliary Currents	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 201.8.7	0.1 mA to 1000 mA
		Linear Movements Of The Patient Support And Gantry	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 201.9.2.4.101.3	0.13 mm to 300 mm
		Reproducibility Of The Radiation Output	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.6.3.2	0.01 mGy to 1000 mGy
		Test For Half-Value Layer	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.7.6	0.1 mmAl to 10 mmAl
		Protection Against Residual Radiation	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.11	0.01 mGy to 1000 mGy

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	Computed tomography Equipment	Protection Against Stray Radiation	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.13	0.01 mGy to 1000 mGy
		CTDI100	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.109.1	0.01 mGy to 1000 mGy
		CTDI free air	IEC 60601-2-44 (3 rd Edition): 2009 Corr. 1: 2009 Amd. 1: 2012 Clause. 203.109.2	0.01 mGy to 1000 mGy
12.	X-ray equipment for interventional procedures	Ingress of water or (Particulate matter into ME Equipment and ME Systems (Footswitches)	IEC 60601-2-43 (2 nd Edition): 2010 Clause. 201.11.6.5.101	1 mm to 300 mm, 0.1 s to 1 hr
		Dosimetric indications	IEC 60601-2-43 (2 nd Edition): 2010 Clause. 203.6.4.5	0.01 mGy to 1000 mGy
		Range Of Air Kerma Rates In Radioscopy	IEC 60601-2-43 (2 nd Edition): 2010 Clause. 203.6.101	0.01 mGy/h to 1000 mGy/h
		Correspondence Between X-Ray Field And Effective Image Reception Area	IEC 60601-2-43 (2 nd Edition): 2010 Clause. 203.8.5.3 IEC 60601-2-54 (3 rd Edition): 2009 Corr. 1: 2010 Clause. 203.8.5.3	1 m to 3 m

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	X-ray equipment for interventional procedures	Designated Significant Zones Of Occupancy	IEC 60601-2-43 (2 nd Edition): 2010 Clause. 203.13.4	0.001 µGy/h to 1000 µGy/h, 0.598 m to 3 m
13.	X-ray Equipment for Radiography and Radioscopy	Leakage Currents And Patient Auxiliary Currents	IEC 60601-2-54 (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.8.7 IS 13450 (Part 2/Sec 54): 2016 Clause. 201.8.7	0.1 mA to 1000 mA
		Reproducibility Of Radiation Output In Radiography	IEC 60601-2-54 (1 st Edition): 2009 Corr. 1: 2010 Clause. 203.6.3.2.101 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.3.2.101	0.01 mGy to 1000 mGy
		Linearity And Constancy In Radiography	IEC 60601-2-54, (1 st Edition): 2009 Corr. 1: 2010 Clause. 203.6.3.2.102 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.3.2.102	0.01 mGy to 1000 mGy
		Accuracy Of X-Ray Tube Voltage	IEC 60601-2-54, (1 st Edition): 2009 Corr. 1: 2010 Clause. 203.6.4.3.104.30 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.4.3.104.30	35 kVp to 120 kVp

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	X-ray Equipment for Radiography and Radioscopy	Accuracy Of X-Ray Tube Current	IEC 60601-2-54(1st Edition): 2009 Corr. 1: 2010 Clause. 203.6.4.3.104.4 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.4.3.104.4	0.1 mA to 500 mA
		Accuracy Of Loading Time	IEC 60601-2-54(1st Edition): 2009 Corr. 1: 2010 Clause. 203.6.4.3.104.5 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.4.3.104.5	1 ms to 30 ms
		Accuracy Of Current Time Product	IEC 60601-2-54, (1st Edition): 2009 Corr. 1: 2010 Clause. 203.6.4.3.104.6 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.6.4.3.104.6	0.1 mA to 500 mA, 1 ms to 30 ms
		Speed Of Movement(S)	IEC 60601-2-54, (1 st Edition): 2009 Corr. 1: 2010 Clause. 201.9.2.2.6 IS 13450 (Part 2/Sec 54): 2016 Clause. 201.9.2.2.6	1 mm to 300 mm
		Attenuation Of The X-Ray Beam Between The Patient And The X-Ray Image Receptor	IEC 60601-2-54, (1st Edition): 2009 Corr. 1: 2010 Clause. 203.10.1 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.10.1	0.1 mmAl to 10 mmAl

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	X-ray Equipment for Radiography and Radioscopy	Determining the attenuation of Residual Radiation	IEC 60601-2-54, (1st Edition): 2009 Corr. 1: 2010 Clause. 203.11.102 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.11.102	0.001 μ Gy/h to 1000 μ Gy/h
		Stray Radiation In Significant Zones Of Occupancy	IEC 60601-2-54, (1st Edition): 2009 Corr. 1: 2010 Clause. 203.13.4.101 IS 13450 (Part 2/Sec 54): 2016 Clause. 203.13.4.101	0.01 mGy to 1000 mGy
14.	Dental intra-oral X-ray Equipment	Leakage Currents And Patient Auxiliary Currents	IEC 60601-2-65, (1st Edition): 2012 Clause. 201.8.7 IS 13450 (Part 2/Sec 65): 2016 Clause. 201.8.7	0.1 mA to 1000 mA
		Protection Against Excessive Temperatures Of X-Ray Monoblock Assemblies	IEC 60601-2-65, (1st Edition): 2012 Clause. 201.11.101 IS 13450 (Part 2/Sec 65): 2016 Clause. 201.11.101	20 °C to 400 °C
		Adjustment Of Radiation Dose And Radiation Quality	IEC 60601-2-65, (1st Edition): 2012 Clause. 203.6.3.1 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.3.1	0.01 mGy to 1000 mGy

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Dental intra-oral X-ray Equipment	Linearity Of Air Kerma	IEC 60601-2-65, (1 st Edition): 2012 Clause. 203.6.3.1.101 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.3.1.101	0.01 mGy to 1000 mGy
		Coefficient Of Variation Of The Air Kerma	IEC 60601-2-65, (1 st Edition): 2012 Clause. 203.6.3.2.101 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.3.2.101	0.01 mGy to 1000 mGy
		Accuracy Of X-Ray Tube Voltage	IEC 60601-2-65, (1 st Edition): 2012 Clause. 203.6.4.3.102.2 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.4.3.102.2	0.01 kVp to 150 kVp
		Accuracy Of X-Ray Tube Current	IEC 60601-2-65, (1 st Edition): 2012 Clause. 203.6.4.3.102.3 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.4.3.102.3	0.1 mA to 500 mA
		Accuracy Of Irradiation Time	IEC 60601-2-65, (1 st Edition): 2012 Clause. 203.6.4.3.102.4 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.4.3.102.4	1 ms to 30 ms

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Dental intra-oral X-ray Equipment	Dosimetric indications	IEC 60601-2-65 (1st Edition): 2012 Clause. 203.6.4.5 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.6.4.5	0.01 mGy to 1000 mGy
		Half-Value Layers And Total Filtration In X-Ray Equipment	IEC 60601-2-65(1st Edition): 2012 Clause. 203.7.1 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.7.1	0.1 mmAl to 10 mmAl, 0.01 mGy to 10 Gy
		Positioning Of The Patient And Restriction Of The Irradiated Area	IEC 60601-2-65, (1st Edition): 2012 Clause. 203.8.5.4 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.8.5.4	1 mm to 300 mm
		Protection Against Residual Radiation	IEC 60601-2-65, (1st Edition): 2012 Clause. 203.11 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.11	0.001 µGy/h to 1000 µGy/h
		Leakage Radiation In The Loading State	IEC 60601-2-65, (1st Edition): 2012 Clause. 203.12.4 IS 13450 (Part 2/Sec 65): 2016 Clause. 203.12.4	0.001 µGy/h to 1000 µGy/h

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15.	X-ray tube assemblies for medical diagnosis	Maximum temperature during NORMAL USE	IEC 60601-2-28 (2 nd Edition): 2010 Clause. 201.11.1.1	20 °C to 400 °C
16.	Radiotherapy Simulator Equipment	Allowable values	IEC 60601-2-29 (3 rd Edition): 2008 Clause. 201.8.7.3	0.1 mA to 1000 mA
		Angular movements	IEC 60601-2-29 (3 rd Edition): 2008 Clause. 201.9.2.2.6.102	1° to 90 °
		Linear movements	IEC 60601-2-29 (3 rd Edition): 2008 Clause. 201.9.2.2.6.103	1 ° to 90 °
		Accuracy of positioning	IEC 60601-2-29 (3 rd Edition): 2008 Clause. 201.9.2.3.102	1 mm to 300 mm, 0.1 s to 1 hr
17.	Photovoltaic			
a.	Thin-film terrestrial photovoltaic (PV) modules - Design qualification and type approval	Visual inspection	IEC 61646 (2 nd Edition): 2008-05, Clause. 10.1	1 lux to 2000 lux ,
		Maximum power determination	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.2 IEC 60904-9, IEC 60904-6, IEC 60904-1, IEC 60891	250 V, 24 A

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Thin-film terrestrial photovoltaic (PV) modules - Design qualification and type approval	Insulation Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.3	1 Vdc to 1 kVdc, 1 kΩ to 5000 MΩ
		Wet leakage current Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.15	1 Vdc to 1 kVdc, 1 kΩ to 5000 MΩ
		Measurement of temperature coefficients	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.4 IEC 60904-10, IEC 60904-9, IEC 60904-1.	Low – 10 °C High – 100 °C 250 V, 24 A
		Measurement of nominal operating cell temperature (NOCT)	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.5	Tilt angle: 45 ° 250 V, 24 A Outdoor Testing
		Performance at STC and NOCT	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.6 IEC 60904-9, IEC 60904-1.	Low – 10 °C High – 100 °C Voltage:- 250 V Current:- 25 A
		Performance at low irradiance	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.7 IEC 60904-9, IEC 60904-1	25 °C 250 V, 24 A
		Outdoor exposure Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.8 IEC 60721-2-1.	60 kWh/m ² Tilt angle 45 ° 600 V ac

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Thin-film terrestrial photovoltaic (PV) modules - Design qualification and type approval	Hot-spot endurance Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.9 IEC 60904-9, IEC 60904-1.	25 °C, 250 V, 24 A
		UV preconditioning Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.10	60 °C ± 5 °C UVA – 15 kWh/m ² UVB – 3 % to 10 % of UVA
		Thermal cycling Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.11	(-)65 °C to 150 °C RH 35 % to 95 %
		Humidity-freeze Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.12	(-)65 °C to 150 °C, RH = 35 % to 95 %
		Damp heat Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.13	20 °C to 85 °C, RH= 85 %
		Robustness of terminations Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.14	200 Nm
		Mechanical load Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.16	2400 Pa 5400 Pa
		Hail Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.17	Ice ball = 25 mm diameter, Mass= 7.53 g, Velocity = 23 m/s.

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Thin-film terrestrial photovoltaic (PV) modules - Design qualification and type approval	Bypass diode thermal Test	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.18	10 °C to 75 °C , Current – 30 A
		Light Soaking	IEC 61646 (2 nd Edition): 2008-05. Clause. 10.19	NA
b.	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Preconditioning	IEC 61215 (2 nd Edition): 2005-04	5.5 kWhrs/m ²
		Visual inspection	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.1) IEC 61730 (1 st Edition): 2004-10 (Clause. 10.1, MST 01) IS 14286 (1 st Edition): 1995-11 (Clause. 10.1)	1 lux to 2000 lux
		Maximum power determination / Voltage , current and power measurements Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.2) UL 1703 (3 rd Edition): 2002-15 (Clause. 20) IS 14286, (1 st Edition): 1995-11 (Clause. 10.2)	250 V, 24 A

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Insulation Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.3) IS 14286 (1 st Edition): 1995-11 (Clause. 10.3)	1 V to 10 kV ac/dc 1 V to 1000 Vdc, 1 kΩ to 5000 MΩ
		Wet leakage current Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.15) IEC 61730 (1 st Edition): 2004-10 (Clause. 10.15, MST 17) IS 14286, (1 st Edition): 1995-11, Clause. 10.15	1 Vdc to 1000 Vdc 1 kΩ to 5000 MΩ
		Measurement of temperature coefficients	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.4) IS 14286, (1 st Edition): 1995-11 (Clause. 10.4)	25 °C to 100 °C 250 V, 24 A
		Measurement of nominal operating cell temperature (NOCT)	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.5) IS 14286, (1 st Edition): 1995-11, Clause. 10.5	Tilt angle: 45 ° 250 V, 24 A 25 °C to 100 °C
		Performance at STC and NOCT	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.6) IS 14286, (1 st Edition): 1995-11 (Clause. 10.6)	30 °C to 100 °C 250 V, 24 A

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Performance at low irradiance	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.7) IS 14286 (1 st Edition): 1995-11 (Clause. 10.7)	250 V, 24 A
		Outdoor exposure Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.8) IS 14286, (1 st Edition): 1995-11 (Clause. 10.8)	Tilt angle: 45 ° 60 kWh/m ² 600 V ac 10 A ac
		Hot-spot endurance Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.9) IS 14286 (1 st Edition): 1995-11 (Clause. 10.9) IEC 61730-2 (Edition 1.1): 2012-11, MST 22	250 V, 24 A
		Thermal cycling Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.11) IEC 61730 (1 st Edition): 2004-10 MST 51 IS 14286 (1 st Edition): 1995-11 (Clause. 10.11) UL 1703 (3 rd Edition): 2002-03 (Clause. 35)	(-)65 °C to 150 °C

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Humidity-freeze Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.12) IEC 61730 (1 st Edition): 2004-10 MST 52 UL 1703 (3 rd Edition): 2002-03 (Clause. 36) IS 14286 (1 st Edition): 1995-11 (Clause. 10.12)	(-)65 °C to 150 °C, 35 % Rh to 95 %Rh
		Damp heat Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.13) IEC 61730 (1 st Edition): 2004-10 MST 53 IS 14286 (1 st Edition): 1995-11 (Clause. 10.13)	20 °C to 150 °C, 35 %Rh to 85 % Rh
		UV preconditioning Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.10) IEC 61730 (1 st Edition): 2004-10 MST 54 IS 14286 (1 st Edition): 1995-11 (Clause. 10.10)	60 °C (±)5 °C., UVA – 15 kWh/m ² UVB – 3 % to 10 % of UVA
		Bypass diode thermal Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.18) IEC 61730 (1 st Edition): 2004-10 MST 25 IS 14286 (1 st Edition): 1995-11 (Clause. 10.18)	10 °C to 75 °C , 0.1 A to 60 A dc

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Partial discharge Test	IEC 61730 (1 st Edition): 2004-10 Clause. 11.1 MST 15	1Vdc to 10 kV dc 2.5 pC to 50 pC
		Impulse voltage Test	IEC 61730 (1 st Edition): 2004-10 (Clause. 10.5 MST 14)	1 kV to 10 kV dc
		Accessibility Test	IEC 61730 (1 st Edition): 2004-10 (Clause. 10.2 MST 11)	
		Cut susceptibility Test	IEC 61730 (1 st Edition): 2004-10 (Clause. 10.3 MST 12)	
		Temperature Test	IEC 61730 (1 st Edition): 2004-10 (Clause. 10.7 MST 21) UL 1703 (3 rd Edition): 2002-03 (Clause. 19)	20 °C to 200 °C Irradiance < 700 W/m ²
		Leakage Current Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 21)	1000 Vdc Resistor- 500 Ω
		Cut Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 24)	
		Bonding Path resistance Test / Ground continuity Test	IEC 61730 (Edition 1.1): 2012-11 (Clause. 10.4) MST 13 UL 1703 (3 rd Edition): 2002-03 (Clause. 25)	1 A to 20 A

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Dielectric Withstand Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 26) IEC 61730 (Edition 1.1): 2012-11 (Clause. 10.6) MST 16	1 Vdc to 10 kVdc 10 s to 900 s
		Wet Insulation-Resistance Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 27)	1 Vdc to 1000 Vdc 1 kΩ to 5000 MΩ
		Reverse Current Overload Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 28) IEC 61730 (Edition 1.1): 2012-11 (Clause. 10.9 MST 26)	1 A to 30 A dc
		Hot-Spot Endurance Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 39)	NA
		Mechanical load Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.16) IEC 61730 (1 st Edition): 2004-10 (Clause. 10.16) IS 14286 (1 st Edition): 1995-11 (Clause. 18)	2400 Pa 5400 Pa

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Crystalline silicon terrestrial photovoltaic (PV) modules - Design qualification and type approval	Hail Test	IEC 61215 (2 nd Edition): 2005-04 (Clause. 10.17) IS 14286 (1 st Edition): 1995-11 (Clause. 21)	Ice ball = 25 mm diameter, Mass = 7.53g, Velocity = 23 m/s
		Module breakage Test	IEC 61730 (1 st Edition): 2004-10 (Clause. MST 32)	Impactor = 45.5 kg 300 mm to 3000 mm
		Strain Relief Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 22)	Load = 20 lb
		Push Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 23)	20 lb (89 N) force applied by a 1/2-in (12.7 mm) diameter steel rod 2. A 4 lb (17.8 N) force applied by a 1/16-in (1.6 mm) diameter steel rod
		Terminal Torque Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 29)	1 Nm to 200 Nm
		Impact Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 30)	50 mm Dia, 1.18 lb (535 g)
		Water Spray Test	UL 1703 (3 rd Edition): 2002-03 (Clause. 33)	10 Psi

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c.	Solar Photovoltaic modules, power conversion units and equipment which are intended for Corrosive environment	Salt Mist Test	IEC 61701 (1 st Edition): 1995-03 (Clause. 4) IEC 61701 (2 nd Edition): 2011-12 IEC 60068-2-52 (2 nd Edition): 1996 IEC 60068-2-11 (3 rd Edition): 1981 (Clause. 4)	25°C to 50°C 95% RH 2000 l 40°C, 95 % RH Size: W =1.82 m, D =1.82 m H = 2.38 m
d.	Photovoltaic Systems -Power Conditioners - Procedure for measuring Efficiency (Stand Alone Inverter & Grid Tie Inverter)	Efficiency	IEC 61683 (1 st Edition): 1999-11	Resistive load till 50 kW and 0.8 PF of Inductive load till 50 kVA. Capacitive load till 50 kVA 5 V to 1000 V dc 200 mA to 100 A dc 60 W to 30 kW
e.	Utility-Interconnected Photovoltaic Inverters-Test Procedure of Islanding Prevention Measures (Grid Tie Inverter)	Test procedure to evaluate the Performance of Islanding Prevention Measures used with Utility-Interconnected PV systems / Un-intentional Islanding Test	IEC 62116 (Edition 2.0): 2014 IEEE 1547.1: 2005, Clause. 5.7	1 V to 1000 V dc 200 mA to 100 A dc 1.5 V to 1000 V 6 A to 200 A, RLC Load: R = 54.3 kW L = 54.3 kVA C = 54.3 kVA

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
f.	Test Procedure for Equipment Interconnecting Distributed Resources with Electric Power Systems	Temperature stability	IEEE 1547.1: 2005, Sec 5.1	RLC Load: R = 54.3 kW L = 54.3 kVA C = 54.3 kVA 6 A to 200 A, ac/dc 15 V to 1000 V, ac/dc 200 mA to 50 A, 3.0000 W to 150.00 kW 15 V to 1000 V ac/dc 5 mA to 65 A ac/dc 5 V to 1000 V dc 200 mA to 100 A dc
Over/Under Voltage Test for Response to Abnormal Voltage Conditions		IEC 61727 (2ndEdition): 2004, Clause:- 5.2 IEEE 1547.1: 2005, Sec 5.2	150/300 V ac	
Over/Under frequency Response to abnormal frequency conditions		IEC 61727 (2 nd Edition): 2004, Clause. 5.2 IEEE 1547: 2005 Sec 5.3	16/819 Hz	
Synchronization		IEEE 1547.1: 2005 Sec 5.4	1 to 30 kVA	
Limitation of dc Injection for Inverters without Interconnection transformers/dc Injection		IEEE 1547.1: 2005, Sec 5.6, IEC 61727 (2 nd Edition): 2004 Clause. 4.4	1 to 30 kVA	

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Test Procedure for Equipment Interconnecting Distributed Resources with Electric Power Systems	Reconnect following abnormal condition disconnect or Response to Utility Recovery	IEEE 1547.1: 2005, Clause. 5.10 IEC 61727 (2 nd Edition): 2004, Clause. 5.4	1 to 50 kVA
		Harmonics &Waveform Distortion	IEC 61727 (2 nd Edition): 2004-12, Clause: 4.6 IEEE 1547.1- 2005, Sec 5.11	1 to 50 kVA
		Flicker	IEC 61727 (2 nd Edition): 2004, Clause: 4.3 IEEE 1547.1: 2005, Sec 5.12,	1 to 50 kVA
		Dielectric Test for Paralleling device	IEEE 1547.1: 2005, Sec 5.5.3	1 to 50 kVA
g.	Balance-of-Systems Components for Photovoltaic Systems-Design Qualification Natural Environments (Solar Photovoltaic Charge Controller)	Visual Inspection	As per MNRE Guidelines for Solar Charge Controller Testing with reference to clauses from IEC 62093	Upto 2 kW, 40 V dc
		Functioning Tests	Clause. 11.1,	Upto max 10 V.
		Voltage Drop Test	Clause. 11.2,	500 V, 100 MΩ
		Insulation Test	Clause. 11.3.1.2,	0.7 Nm
		Protection Against Mechanical Impact(IK-code)	Clause. 11.4, Clause. 11.6, Clause. 11.2.1.2.3.1, Clause. 11.2.1.2.3.3, Clause. 11.3.1.1	7.1 V to 35.5 V
		Determination of End of Charge Voltages		

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	Balance-of-Systems Components for Photovoltaic Systems-Design Qualification Natural Environments (Solar Photovoltaic Charge Controller)	Determination of Low Charge disconnect and Reconnect Voltages		5.1 V to 35.7 V
		Temperature Compensation for Thresholds		7.1 V to 35.5 V Temperature for all ranges defined in standard.
		Cold Test (Type Ad)	IEC 60068-2-1 Environmental Testing – (Part 2 to 1): Tests – Test A: COLD Edition 6 Date. 2007/03/01	Test Conditions: (-)10 °C (±) 3 °C for 2 hr.
		Rapid change of temperature with prescribed time of transfer:	IEC 60068-2-14 Environmental Testing – (Part 2 to 14): Tests – Test N: CHANGE OF TEMPERATURE - Edition): 6 - Issue Date 2009/01/01	Test Conditions: (-)5 °C & (+)55 °C (±)3 °C
		Dry Heat Test (Type Bd)	IEC 60068-2-2 Environmental Testing – (Part 2 to 2): Tests – Test B: DRY HEAT - Edition): 5 - Issue Date 2007/07/01	Test Conditions: (+)55 °C (±)2 °C
	Damp Heat (Type Db Variant 1)	IEC 60068-2-30 Environmental Testing (Part 2 to 30): Tests – Test DB: DAMP HEAT, CYCLIC (12 H + 12 H CYCLE) – (Edition 3) Date. 2005/08/01	Test Conditions: Temperature: 25 °C to 55 °C (±)2 °C, variant 1, Humidity: 93(±)3 % RH	

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18.	Measuring Instruments			
a.	Electronic Equipment – Digital millimeter, digital power meter, clamp meter, digital ammeter, Digital voltmeter, Digital panel power meter	Protective impedance Test	UL 61010-1 (2 nd Edition) 2005-07-22. CAN/CSA C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 4.4.2.2) IEC 61010-2-030: 2010, (1 st Edition). (Clause. 101.3.3)	20 to 400 °C
Input Test		UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA C22.2 No. 61010-1, (2 nd Edition):004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 5.1.3)	0.1 V to 600 V AC 10 A max 0.1 V to 600 V DC	
Temperature Test		UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010 (3 rd Edition) (Clause. 10.1-10.4)	20 to 400 °C Qualitative	

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	Electronic Equipment – Digital millimeter, digital power meter, clamp meter, digital ammeter, Digital voltmeter, Digital panel power meter	Humidity conditioning	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 6.8.2)	50 % RH to 98 % RH (-)20 °C to100 °C Qualitative
		Dielectric voltage withstand Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 6.8)	10 V to 10 kV AC/DC 10 s to 900 s Qualitative
		Permissible limits Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 6.3)	0.1 V to 300 V AC/DC
		Transformer overload Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 4.4.2.7.3)	20 to 400 °C Qualitative

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	Electronic Equipment – Digital millimeter, digital power meter, clamp meter, digital ammeter, Digital voltmeter, Digital panel power meter	Transformer short circuit Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 4.4.2.7.2)	1 to 600 V 1 to 1000 V AC/DC 20 to 400 °C
		Insulation between circuits	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 4.4.2.12)	1 to 600 V 1 to 1000 V AC/DC 20 to 400 °C
		Output abnormal Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA-C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 4.4.2.8)	600 V 1 to 1000 V AC/DC 20 to 400 °C
		Applied force Test	UL 61010-1 (2 nd Edition): 005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 6.2.2)	1 to 50 kg Qualitative

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	Electronic Equipment – Digital millimeter, digital power meter, clamp meter, digital ammeter, Digital voltmeter, Digital panel power meter	Ball pressure Test	UL 61010-1 (2 nd Edition): 005-07-22. CAN/CSA-C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 10.5.3)	20 to 150 °C 0.01 mm to 10 mm Qualitative
		Static rigidity Test	UL 61010-1 (2 nd Edition): 005-07-22. CAN/CSA-C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 8.2.1)	1 to 50 kg 20 to 150 °C Qualitative
		Strength of Handle Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA-C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 7.5)	10 g to 80 kgs 0.1 s to 1 hr Qualitative
		Mechanical abuse Test	UL 61010-1 (2 nd Edition): 2005-07-22. CAN/CSA –C22.2 No. 61010-1, (2 nd Edition): 004-07, IEC 61010-1: 2010, (3 rd Edition) (Clause. 10.5.2)	1 Nm to 6.78 Nm Qualitative

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electronic Equipment – Digital millimeter, digital power meter, clamp meter, digital ammeter, Digital voltmeter, Digital panel power meter	Impulse voltage Test	IEC 61010-2-030: 2010, (1.0 Edition) (Clause. 14.101)	Upto 15 kV, 1.2/50 μs Impulse Qualitative
		Current measuring circuit Test	IEC 61010-2-030: 2010, (Edition 1.0) (Clause. 14.101)	Upto 200 A AC single phase AC Single Phase 50 Hz Continuous
19.	Electrical & electronics products (IFM modules, Storages, servers)	Sine and random vibration Test, Qualitative	IEC 60068-2-6: 2007 IEC 60068-2-64: 2008	Frequency – 5 Hz to 2300 Hz. Acceleration level: 0.3 g to 100 g for Frequency from 5 Hz to 2300 Hz,
	Cabinets, Racks, Sub racks, Chassis	Sine and random vibration Test, Qualitative	IEC 61587-1: 2011 IEC 62052-11: 2003	0.1 g to 100 g for Frequency from 5 Hz to 600 Hz} for weight Upto 3.5 kg.
	Printed circuit boards	Sine and random vibration	IEC 60065: 2014 IEC 62133: 2002	0.1 g to 50 g (P-P). 5 Hz to 600 Hz for weight Upto 3.5 kg.
	Aerospace products (signal trackers, Navigation sensors, voice receivers, Timers)	Sine and random vibration Sine and random vibration	MIL-STD-810G: 2008 (Method 514.6C-I) MIL STD 810F: 2000 Method 514.5(514.6C-1)	0.1 g to 50 g (P-P). 0.3 g to 6 g for weight Upto 400 kg. Displacement Upto 50.8 mm Frequency – 5 Hz to 2300 Hz.

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Consumer products (Amplifier, Mosfet transistors, luminares)	Sine and random vibration	MIL STD 883E: 1997 Method 2007.2, 2002 & 2026 MIL STD 202G: 2002 Method 201A (2.4.1-Part 1)	Acceleration level: {0.3 g to 100 g for Frequency from 5 Hz to 2300 Hz, 0.1 g to 100 g for Frequency from 5 Hz to 600 Hz} for weight Upto 3.5 kg. 0.1 g to 50 g (P-P). 5 Hz to 600 Hz} for weight Upto 3.5 kg. 0.1 g to 50 g(P-P). 0.3 g to 6 g for weight Upto 400 kg. Displacement Upto 50.8 mm
	Railway mounted and railway transporting products(AC and exhaust fan)	Random vibration	IEC 61373: 2010	Range
	Batteries and Cells phones, Laptops, Power banks	Sine vibration	UN38.3 (Edition 6): 2015 (38.3.4.3)	7Hz: 200Hz-7Hz,Disp(0.8 mm-1.6 mm)Acceleration 8g

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
20.	Power adaptors , inverters,Energy meters, Signal control receivers Motors, TV's, laptops, Mobile phones aerospace products (signal trackers, Navigation sensors, voice receivers, Timers)	Shock Test (Electro dynamic shaker)-Half sine, rectangular, Trapezoidal, Final peak saw tooth, Initial saw tooth.	IEC 60068-2-27: 2008 IEC 61587-1: 2011 IEC 62052-11: 2003 IEC 62052-11: 2003 MIL-STD-810G: 2008, Method 514.6 MIL STD 810F: 2000 Method 514.5 MIL STD 202G: 2002 Method 201A	Acceleration level-35 g, 11 ms, 1 g, 50 ms.
	Railway mounted and railway transporting Products(AC and exhaust fan)	Shock Test (Electro dynamic shaker)-Half sine, rectangular, Trapezoidal, Final peak saw tooth, Initial saw tooth	IEC 61373: 2010	

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	PCB mounted Electrical & electronics Products(Energy meters, Control receivers Mobile phones, TV, scanner, Battery chargers) Racks& Chassis	Mechanical Shock-Half sine, Trapezoidal, saw tooth, Qualitative	IEC 60068-2-27: 2008 IEC 62052-11: 2003 IEC 61587-1: 2011	Half sine pulse range: 600 g to 3 ms; 20 g, (-)35 ms. Trapezoidal pulse range: 75 g to 10 ms; 10 g to 50 ms. Max specimen weight: 50 kg. Table size: (25 x 25)cm
	Batteries and Cells	Mechanical Shock-Half sine, Trapezoidal , saw tooth, Qualitative	UN38.3(Edition 6): 2015	
21.	Spares & Assemblies mounted in Defense/ Military/ Aerospace(signal trackers, Navigation sensors,voice receivers, Timers) Locomotive Transport vehicles mounted products (AC, exhaust fan, Diesel filters, ECU)	Mechanical Shock-Half sine, Trapezoidal , saw tooth, Qualitative	MIL-STD-810G: 2008, Method 516.6 MIL STD 810F: 2000 Method 516.5 MIL STD 883E: 1997 Method 2002.3	Half sine pulse range: 600 g to 3 ms; 20 g, (-)35 ms. Trapezoidal pulse range: 75g-10ms; 10 g to 50 ms. Max specimen weight: 50 kg. Table size: (25 x 25)cm

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Railway mounted and railway transporting Products(AC and exhaust fan)	Mechanical Shock-Half sine, Trapezoidal , saw tooth, Qualitative	MIL STD 202G: 2002 Method 213 B IEC 61373: 2010	
22.	Batteries & Cells, Spares and assemblies in aircraft (signal trackers, Navigation sensors,voice receivers,Timers). Helicopters and manned aerospace vehicles(Amplifier Mosfet transistors, Luminaires)	Altitude Test Qualitative Combined cold/low air pressure Tests-Qualitative	IEC 60068-2-13-1994 IEC 60721-1: 2002 (1.3) IEC 62133: 2002 MIL STD 810F: 2000 Method 500.4-1 MIL-STD-810F: 2000 Method 507.4 IEC 60068-2-40-1983 MIL-STD-810F: 2000 Method 500.4-1 MIL-STD-810G: 2008 Method 500.5-1 MIL-STD-810G: 2008 Method 520.3	Altitude range: Pressure Upto 25,800 m,10 mbar Altitude range: Pressure Upto 19,000 m, 5.3 kPa. Temperature range: Upto (-) 40 °C.

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V. EMI/EMC AND ESD TESTING

1.	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Conducted Emission Test (CE)	IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0) (2014-04) IEC 61000-6-3 (2 nd Edition)-1 (2011-02) IEC 61000-6-4 (2 nd Edition)-1 (2011-02) IEC 61326-1 (2 nd Edition)-0 (2012-07) IEC 62040-2 (2 nd Edition)-0 (2005-10) IEC 62052-11 (Edition 1.0) (2003-02) IEC 60034-1 (Edition 12.0): (2010-02) CISPR 11: 2015/Amd. 1: 2016 CISPR 11: 2015/Amd. 1: 2016 CISPR 14-1 (Edition 5.0): (2005-11) CISPR 14-1 (Edition 5.1): (2009-02) CISPR 14-1 (Edition 5.2): (2011-11) CISPR 15 (Edition 8): (2013-05) CISPR 22 (Edition 6.0): (2008-09) EN 55011: 2010	Frequency Range: 9 kHz to 30 MHz Current limitation): of Max 16 A for 1Phase Max 25 A for 3 Phase
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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
			EN 50121-3-2: 2015 EN 55014-1: 2006+ Amd. 2: 2011 EN 55015: 2006+ Amd. 2: 2009 EN 55015: 2013 EN 55022: 2010/AC 2011 EN 60601-1-2: 2007/AC: 2010 EN 61000-6-3: 2007/A1: 2011 EN 61000-6-4: 2007/A1: 2011 EN 61326-1: 2013 EN 62040-2: 2006 EN 62052-11: 2003 EN 50121-4: 2006 CFR 2010 Title 47 Vol.1 (Part 15) CFR 2010 Title 47 Vol.1 (Part 18) IS 16102-2, Clause. 16.1 IS 6873-5 IS 13779: 1999 (RA 2009) IS 6842: 1997 IS 14697: 1999, (RA 2009)	
		Radiated Electromagnetic Disturbances	CISPR 15 (Edition 7.2): (2009-01) Clause. 4.4.1 EN 55015: 2006+ Amd. 2: 2009 Clause. 4.4.1 IS 16102-2, Clause. 16.1 IS 6873-5	Frequency Range: 9 kHz to 30 MHz

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	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Harmonic Current Emission Test	IEC 61000-3-2 (Edition 4): (2014-05) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-3 (Edition 2.1): (2011-02) IEC 61326-1 (Edition 2.0): (2012-07) EN 60601-1-2: 2007/AC: 2010 EN 61000-3-2: 2006 Amd. 2: 2009 EN 61000-3-2: 2014 EN 61000-6-3: 2007 Amd. 1: 2011 EN 61326-1: 2013	Current limitation: 16 A, 1phase upto 40 th Harmonic Line to Neutral Voltage: 100 to 120 & 220 V to 250 V Frequency 50 Hz/60 Hz
		Voltage Fluctuation & Flicker Test	IEC 61000-3-3 (Edition 3.0): (2013-05) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-3 (Edition 2.1): (2011-02) IEC 61326-1 (Edition 2.0): (2012-07) EN 60601-1-2: 2007/AC: 2010 EN 61000-3-3: 2008 EN 61000-3-3: 2013	Current limitation): 16 A Single Phase Line to Neutral Voltage: 100 to 120 & 220 V to 250 V

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Voltage Fluctuation & Flicker Test	EN 61000-6-3: 2007, Amd. 1: 2011 EN 61326-1: 2013	Current limitation): 16 A Single Phase Line to Neutral Voltage: 100 to 120 & 220 V to 250 V
		Electrostatic Discharge Immunity Test	IEC 61000-4-2 (Edition 2.0): (2008-12) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-1 (2 nd Edition)-0 (2005-03) IEC 61000-6-2 (Edition 2.0) (2005-01) IEC 61326-1 (2 nd Edition)-0 (2012-07) IEC 62040-2 (2 nd Edition)-0 (2005-10) IEC 62052-11 (Edition 1.0): (2003-02) IEC 61547 (Edition 2.0): 2009-06 CISPR 14-2(Edition 2.0) : 2015 RLV CISPR 24 (Edition 2.0): (2010-08) EN 61000-4-2: 2009 EN 50121-3-2: 2015 EN 50121-4: 2006	Voltage Range: Air discharge: 0.2 kV to 16 kV Contact Discharge: 0.2 kV to 10 kV

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	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Electrostatic Discharge Immunity Test	EN 55014-2: 1997/ Amd. 2: 2008 EN 55024: 2010 EN 60601-1-2: 2007/AC: 2010 EN 61000-6-1: 2007 EN 61000-6-2: 2005 EN 61326-1: 2013 EN 62040-2: 2006 EN 62052-11: 2003 EN 61547: 2009 IS 13779: 1999 (RA 2009) IS 14697: 1999 (RA 2009)	Voltage Range: Air discharge: 0.2 kV to 16 kV Contact Discharge: 0.2 kV to 10 kV
		Electrical Fast Transient (EFT) / Burst Immunity Test	IEC 61000-4-4 (Edition 3.0): (2012-04) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-1 (2 nd Edition): (2005-03) IEC 61000-6-2 (2 nd Edition): (2005-01) IEC 61326-1 (2 nd Edition): (2012-07) IEC 62040-2 (2 nd Edition): (2005-10) IEC 62052-11 (Edition 1.0): (2003-02) IEC 61547: 2009 CISPR 14-2(Edition 2.0):	Current limitation: Max 16 A for 1 phase Max 32 A for 3 Phase Voltage Limitations: 0.2 kV to 4 kV for 3Ph Max: 0.2 kV to 5.5 kV for 1Ph

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	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Electrical Fast Transient (EFT) / Burst Immunity Test	2015 RLV CISPR 24 (2 nd Edition): (2010-08) EN 61000-4-4: 2012 EN 55014-2: 1997/ Amd. 2: 2008 EN 55024: 2010 EN 60601-1-2: 2007/AC 2010 EN 61000-6-1: 2007 EN 61000-6-2: 2005 EN 50121-3-2: 2015 EN 50121-4: 2006 EN 61326-1: 2013 EN 62040-2: 2006 EN 62052-11: 2003 EN 61547: 2009 IS 13779: 1999 (RA 2009) IS 14697: 1999 (RA 2009)	Current limitation: Max 16 A for 1 phase Max 32 A for 3 Phase Voltage Limitations: 0.2 kV to 4 kV for 3Ph Max: 0.2 kV to 5.5 kV for 1Ph
		Surge Immunity Test	IEC 61000-4-5 (Edition 3.0): (2014-05) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-1 (2 nd Edition): (2005-03) IEC 61000-6-2 (2 nd Edition): (2005-01) IEC 61326-1 (2 nd Edition): (2012-07)	Max 16 A for 1phase Max 32 A for 3 Phase Voltage Rage : 0.25 kV to 6.0 kV for 1 Ph 0.25 kV to 6.0 kV for 3 Ph

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IEC 62040-2 (2nd Edition):
(2005-10)
IEC 62052-11 (Edition 1.0):
(2003-02)
IEC 61547: 2009
CISPR 14-2(Edition 2.0):
2015 RLV
CISPR 24 (2nd Edition):
(2010-08)
EN 61000-4-5: 2006
EN 61000-4-5: 2014
EN 55014-2: 1997/
Amd. 2: 2008
EN 55024: 2010
EN 60601-1-2: 2007/AC 2010
EN 61000-6-1: 2007
EN 61000-6-2: 2005
EN 50121-3-2: 2015
EN 50121-4: 2006
EN 61326-1: 2013
EN 62040-2: 2006
EN 62052-11: 2003
EN 61547: 2009

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	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Conducted RF Immunity Test	IEC 61000-4-6 (Edition 4.0): (2013-10) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-1 (2 nd Edition): (2005-03) IEC 61000-6-2 (2 nd Edition): (2005-01) IEC 61326-1 (2 nd Edition): (2012-07) IEC 62040-2 (2 nd Edition): (2005-10) IEC 62052-11 (Edition 1.0): (2003-02) IEC 61547: 2009 CISPR 14-2(Edition 2.0): 2015 RLV CISPR 24 (2 nd Edition): (2010-08) EN 61000-4-6: 2009 EN 61000-4-6: 2014 EN 50121-3-2: 2015 EN 50121-4: 2006 EN 55014-2: 1997/ Amd. 2: 2008 EN 55024: 2010 EN 60601-1-2: 2007/AC 2010 EN 61000-6-1: 2007 EN 61000-6-2: 2005	150 kHz to 230 MHz 1 Vrms to 10 Vrms CDN Method Power 150 kHz to 230 MHz 1 Vrms to 10 Vrms, EM Clamp Method for I/O Lines.

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Conducted RF Immunity Test	EN 61326-1: 2013 EN 62040-2: 2006 EN 62052-11: 2003 EN 61547: 2009	150 kHz to 230 MHz 1 Vrms to 10 Vrms CDN Method Power 150 kHz to 230 MHz 1 Vrms to 10 Vrms, EM Clamp Method for I/O Lines.
		Power Frequency Magnetic Field Immunity Test	IEC 61000-4-8 (2 nd Edition): (2009-09) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0): (2014-02) IEC 61000-6-1 (2 nd Edition): (2005-03) IEC 61000-6-2 (2 nd Edition): (2005-01) IEC 61326-1 (2 nd Edition): (2012-07) IEC 62040-2 (2 nd Edition): (2005-10) IEC 61547 2009 CISPR 24 (2 nd Edition): (2010-08) EN 61000-4-8: 2010 EN 55024: 2010 EN 60601-1-2: 2007/AC 2010 EN 61000-6-1: 2007 EN 61000-6-2: 2005 EN 61326-1: 2013	1 A/m to 30 A/m 50 Hz/60 Hz Continuous field

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	EMI/EMC and ESD Testing	Power Frequency Magnetic Field Immunity Test	EN 62040-2: 2006 EN 61547: 2009	1 A/m to 30 A/m 50 Hz/60 Hz Continuous field
	EMI-EMC Testing :			
	Electrical and Electronic Instrument	Voltage Dips, Short Interruption & Voltage variations Immunity Test	IEC 61000-4-11 (2 nd Edition): (2004-03) IEC 60601-1-2 (Edition 3.0): (2007-03) IEC 60601-1-2 (Edition 4.0) (2014-02) IEC 61000-6-1 (2 nd Edition): (2005-03) IEC 61000-6-2 (2 nd Edition): (2005-01) IEC 61326-1 (2 nd Edition): (2012-07) IEC 62052-11 (Edition 1.0): (2003-02) IEC 61547: 2009 CISPR 14-2(Edition 2.0): 2015 Rlv CISPR 24 (2 nd Edition): (2010-08) EN 61000-4-11: 2004 EN 55014-2: 1997 Amd. 2: 2008 EN 55024: 2010 EN 60601-1-2: 2007/ AC. 2010 EN 61000-6-1: 2007 EN 61000-6-2: 2005	Single Phase Current limitation): Max 16 A Voltage range : 0.1 to 250 V

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	EMI/EMC and ESD Testing EMI-EMC Testing : Electrical and Electronic Instrument	Voltage Dips, Short Interruption & Voltage variations Immunity Test	EN 61326-1: 2013 EN 62040-2: 2006 EN 62052-11: 2003 EN 61547: 2009	Single Phase Current limitation): Max 16 A Voltage range : 0.1 to 250 V
		Ring wave Immunity Test	IEC 61000-4-12: 2006 EN 61000-4-12: 2006	Current limitation of 16 A for 1 phase 32 A for 3 Phase Max: 6.6 kV

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I. INFORMATION TECHNOLOGY EQUIPMENTS

1. Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Input Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 1.6.2)	1.5 V to 300 VAC/DC 1 mA to 20 A AC/DC
	Thermal requirement	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.5.1)	20 °C to 400 °C
	Overload of operator accessible Parts	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.3.7)	1 W to 330 W(max) 0.1 s to 1 hr
	Humidity conditioning	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.9.1)	93 % to 95 % RH 20 °C to 100 °C Qualitative
	Electric strength Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.2.2)	50 V to 10 kV AC/DC 1 s to 900 s
	Touch current Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.1)	0.1 mA to 5 mA
	Abnormal operation Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.3.1)	25 °C to 400 °C Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Capacitance discharge Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.1.1.7)	0.1 V to 800 V Peak / DC 5 s
		Limited power source measurement Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.5)	1 W to 330 W(max) 0.1 s to 1 hr
		Working voltage determination	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.10.2)	1 V to 1000 V rms/V DC
		Protective bonding Test II	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.6.3.4)	0.01 Ω to 0.3 Ω 5 s to 600 s A to 60 A
		Limited current circuit measurements	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 2.4.1)	0.1 mA to 5 mA
		Limitation of touch current to a telecommunication and cable distribution system	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 5.1.8.1)	0.1 mA to 5 mA
		Requirement of separation between telecommunication network from earth	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 6.1.2)	1 V to 2 kV AC/DC 1-900 s
		Steady force Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.1)	0.1 s to 1 hr 1 N to 900 N Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Impact Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.5)	1 mm to 3000 mm 500 g
		Strain relief Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 3.2.6)	0.1 s to 1 hr 1 N to 60 N Qualitative
		Cord guard Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 3.2.8)	5 ° to 90 ° 15.5 mm to 25 mm
		Hazardous moving Parts Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.4.2)	Test finger - Figure 2A Qualitative
		Stability Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.1)	5 ° to 60 ° Qualitative
		Durability of marking Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 1.7.11)	Qualitative (Visual inspection)
		Stress relief Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.7)	25°C to 150 °C Qualitative
		Drop Test	IS 13252 (Part 1): 2010 + Amd. 1: 2013 +Amd. 2: 2015 (Clause. 4.2.6)	1 mm to 3000 mm Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Input Test	UL 60950-1 (2 nd Edition):2007 CSA C22.2 No. 60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 ((2 nd Edition):2005+ Amd. 1 Date. 2009-12-01 (Clause. 1.6.2) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1: 2001 (1 st Edition) (Clause. 1.6.2)	1.5 V to 300 VAC 1.5 V to 300 VDC 0.5 mA to 20 A AC/DC
		Thermal requirement	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005-12-01 + Amd.1 Date. 2009-12-01(Clause. 4.5.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1(1 st Edition): 2001 (Clause. 4.5.1)	20 °C to 400 °C Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Output overload Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01+ Amd. 1 Date. 2009-12-01 (Clause. 5.3.7) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001	1 W to 330 W(max) 0.1 s to 1 hr
		Dielectric strength Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition) Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 5.2.2) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1(1 st Edition): 2001 (Clause. 5.2)	50 V to 10 kV AC/DC 1 s to 900 s Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Touch current Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005 + Amd. 1 Date. 2009-12-01 (Clause. 5.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 5.1)	0.1 mA to 5 mA
		Output short circuit Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd. 1 Date. 2009-12-01 (Clause. 5.3.7) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 5.3.7)	20 °C to 400 °C Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Abnormal operation Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005 + Amd. 1 Date. 2009-12-01 (Clause. 5.3.3) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1(1 st Edition): 2001 (Clause. 5.3.1)	20 °C to 400 °C Qualitative
		Component failure Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd. 1 Date. 2009-12-01 (Clause. 5.3.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition):2001 (Clause. 5.3.1)	25 °C to 400 °C Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	SELV reliability Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd. 1 Date. 2009-12-01 (Clause. 2.2.2) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 2.2.2)	0.1 V to 90 V Peak
		Max. V, VA, A measurement Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1: (2 nd Edition):2005-12-01+ Amd.1 Date. 2009-12-01 (Clause. 1.2.2.1) UL 60950-1 (1st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1: 2001 (1st Edition) (Clause. 1.2.2.1)	0.1 V to 80 V 0.1 VA to 800 VA 1 mA to 20 A max

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Capacitance discharge Test	UL 60950-1 (2 nd Edition):2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005 + Amd.1 Date. 2009-12-01 (Clause. 2.1.1.7) UL 60950-1 (1 st Edition): 2006/ CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 2.1.1.7)	0.1 V to 800 V Peak / DC 5 s
		Energy hazard measurement Test	UL 60950-1 (2 nd Edition):2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 2.1.1.8) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1: 2001 (1st Edition): (Clause. 2.1.1.8)	0.1 V to 800 V Peak 0.1 s to 10 s

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Limited power source measurement Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 2.5) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 2.5)	1 W to 330 W(max) 0.1 s to 1 hr
		Working voltage measurement Test	UL 60950-1 (2 nd Edition): 2007/03/27 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005-12-01+ Amd.1 Date. 2009-12-01 (Clause. 2.10.2) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1: 2001 (1 st Edition): (Clause. 2.10.2)	1 V to 1000 V rms/VDC

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Transformer and wire insulation electric strength Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 2.10.5.13) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1: 2001 (1 st Edition): (Clause. 2.10.5.13)	10 V to 10 kV AC/DC 1 s to 900 s Qualitative
		Steady force Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 4.2.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 4.2.1)	0.1 s to 1 hr 1 N to 900 N Qualitative

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box	Impact Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 4.2.5) UL 60950-1 (1 st Edition): 2006/07/07 CSA C 22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 4.2.5)	50 mm Dia 500 g Qualitative
		Stress relief Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition) Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 4.2.7) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1(1 st Edition): 2001 (Clause. 4.2.7)	25 °C to 150 °C Qualitative

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
2.	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box (Thermoplastic, Thermoset, Composite Material)	Ball pressure Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01+ Amd.1 Date. 2009-12-01 (Clause. 4.5.5) UL 60950-1 (1 st Edition): 2006 /CSA C22.2 No.60950-1-03/ IEC 60950-1(1 st Edition): 2001 (Clause. 4.5.5)	Loading Device Diameter 5 mm, 20 N max 0.01 mm to 10 mm 0.1 hr to 1 hr Qualitative
		Accessible connector overload Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 5.3.7) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 5.3.7)	1 W to 330 W(max) 0.1 s to 1 hr Qualitative

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	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box (Thermoplastic, Thermoset, Composite Material)	Earthing Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 2.6.3.4) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 2.6.3.4)	0.001 Ω to 0.3 Ω 5 s to 600 s 0.1 A to 60A
		Limited power source measurement Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 2.5) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 2.5)	1 W to 330 W(max) 0.1 s to 1 hr

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Power adaptors, Mobile Phone, Cash Register, Point of Sale Terminal, Copying Machine, Franking Machine, Passport reader, Computer Systems, Monitors, Printers, Scanners, Keyboards, Telephones & Automatic Data Processing Machine, Setup Box (Thermoplastic, Thermoset, Composite Material)	Stability Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 4.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001(Clause. 4.1)	5 ° to 90 ° Qualitative
		Component failure Test	UL 60950-1 (2 nd Edition): 2007 CSA C22.2 No.60950-1 (2 nd Edition): Date. 2007/03/27 IEC 60950-1 (2 nd Edition): 2005/12/01 + Amd.1 Date. 2009-12-01 (Clause. 5.3.1) UL 60950-1 (1 st Edition): 2006/07/07 CSA C22.2 No.60950-1-03/ IEC 60950-1 (1 st Edition): 2001 (Clause. 5.3.1)	(-)100 °C to 400 °C

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
3.	Desktop Computer, Notebook computers, Tablets, Small-scale servers, Thin Client, Workstations and Monitors	Off mode	ENERGY STAR Computer Test Method, Version 6.1 UUT preparation shall be performed according to IEC 62623 (Edition 1.0): 2012-10, Section 5.2: Test Setup	0.1 Wh to 500Wh 5 s to 15 min
		Sleep Mode	ENERGY STAR Computer Test Method, Sleep Mode power shall be measured according to IEC 62623 (Edition 1.0): 2012 10, Section 5.3.3: Measuring Sleep Mode	0.1 Wh to 500Wh 5 s to 15 min
		Idle State	ENERGY STAR Computer Test Method, Long Idle Mode power shall be measured according to IEC 62623 (Edition 1.0): 2012-10, (Section 5.3.4): Measuring Long Idle Mode;	0.1 Wh to 500 Wh 5 s to 15 min
		Active State	ENERGY STAR Computer Test Method, Short Idle Mode power shall be measured according to IEC 62623 (Edition 1.0): 2012-10, (Section 5.3.5): Measuring Short Idle Mode	0.1 Wh to 500 Wh 5 s to 15 min

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Desktop Computer, Notebook computers, Tablets, Small-scale servers, Thin Client, Workstations and Monitors	Idle State	ENERGY STAR Test Method for Computer Servers, Off Mode power shall be measured according to IEC 62623 (Edition 1.0): 2012-10, (Section 5.3.2): Measuring Off Mode	0.1 Wh to 500 Wh 5 s to 15 min
		Full Load	ENERGY STAR Test Method for Computer Servers, ENERGY STAR Program Requirements Product Specification for Computer Servers, Version 1.1, Appendix A	0.1 Wh to 500 Wh 5 s to 10 min
4.	Energy efficiency of Internal/ External AC-DC and DC-DC Power supplies	Active Mode power consumption): for single Output power supply	Generalized Test Protocol for calculating the Energy Efficiency of Internal AC-DC and DC-DC Power supplies: Revision 6.4.2, 22 nd October 2008 & Revision 6.5, July 07, 2010. according to IEC 62623 (Edition 1.0): 2012-10 Test Method for Calculating the Energy Efficiency of Single-Voltage External Ac-Dc and AC-AC Power Supplies August 11, 2004.	0.1 Wh to 500 Wh 5 s to 10 min

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Energy efficiency of Internal/ External AC-DC and DC-DC Power supplies	Active Mode power consumption for multiple Output power supply	Generalized Test Protocol for calculating the Energy Efficiency of Internal AC-DC and DC-DC Power supplies: Revision 6.4.2, 22 nd October 2008 & Revision 6.5, July 07, 2010. According to IEC 62623 (Edition 1.0): 2012-10 Test Method for Calculating the Energy Efficiency of Single-Voltage External AC-DC and AC-AC Power Supplies August 11, 2004	0.1 Wh to 500 Wh 5 s to 10 min
		Standby Mode Power consumption	Generalized Test Protocol for calculating the Energy Efficiency of Internal AC-DC and DC-DC Power supplies: Revision 6.4.2, 22 nd October 2008 & Revision 6.5, July 07, 2010. according to IEC 62623 (Edition 1.0): 2012-10 Test Method for Calculating the Energy Efficiency of Single-Voltage External AC-DC and AC-AC Power Supplies August 11, 2004	0.1 Wh to 500 Wh 5 s to 10 min

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II. AUDIO/ VIDEO COMPONENTS AND PRODUCTS

1.	House Hold Electronic Appliances – CRT TV; LCD; Plasma displays	Standby power measurement	IEC 62301 (Edition 2): 2011-01 IS 13384 (Part 1): 1992 IS 13384 (Part 2): 1997	0.1 Wh to 500 Wh
		On mode Power measurement	IEC 62087 (Edition 3): 2011-04 IS 13384 (Part 1): 1992 IS 13384 (Part 2): 1997	0.1 Wh to 500 Wh
2.	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Normal operating conditions – Input Test	EN/IEC 60065: 2005, Clause. 4.2 IS 616: 2010 Clause. 4.2	1.5 V to 300 VAC 1.5 V to 300 VDC 0.5 mA to 20 A AC/DC
		Marking Legibility	EN/IEC 60065: 2005, Clause. 5 IS 616: 2010, Clause. 5	0.1 s to 600 s Qualitative
		Heating under normal operating conditions	EN/IEC 60065: 2005, Clause. 7 IS 616: 2010, Clause. 7	Upto 400 °C Qualitative
		Hygroscopic materials	EN/IEC 60065: 2005, Clause. 8.3 IS 616: 2010, Clause. 8.3	42 °C 90 % to 95 % Qualitative

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Winding insulation Test	EN/IEC 60065: 2005, Clause. 8.8 IS 616: 2010, Clause. 8.8	10 V to 10 kV AC/DC 10 s to 900 s Qualitative
		External forces – windows & covers	EN/IEC 60065: 2005, Clause. 8.13, 8.14 IS 616: 2010, Clause. 8.13, 8.14	1 N to 50 N 1 S to 10 S Qualitative
		Internal forces	EN/IEC 60065: 2005, Clause. 8.15 IS 616: 2010, Clause. 8.15	1 N to 2 N Qualitative
		Determination of hazardous live Parts	EN/IEC 60065: 2005, Clause. 9.1.1.1 IS 616: 2010, Clause. 9.1.1.1	1 V to 300 V rms/Vdc 0.1 mA to 5 mA
		Protection): against electric shock - Accessibility	EN/IEC 60065: 2005, Clause. 9, 9.1.1.2, 9.2 IS 616: 2010, Clause. 9, 9.1.1.2, 9.2	1 N to 3 N 1 N to 22 N Qualitative
		Protection against electric shock – Opening in enclosure	EN/IEC 60065: 2005, Clause. 9.1.3 IS 616: 2010, Clause. 9.1.3	Test probe (4 mm x 100 mm) Qualitative

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	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Protection against electric shock – Terminals	EN/IEC 60065: 2005, Clause. 9.1.4 IS 616: 2010, Clause. 9.1.4	1 mm to 30 mm 1 N to 11 N Qualitative
		Preset controls	EN/IEC 60065: 2005, Clause. 9.1.5 IS 616: 2010, Clause. 9.1.5	1 N to 150 N Qualitative
		Withdrawal of main plug	EN/IEC 60065: 2005, Clause. 9.1.6 IS 616: 2010, Clause. 9.1.6	0.1 V to 800 V Peak / DC 0.1 s to 10 s
		Resistance to external forces	EN/IEC 60065: 2005, Clause. 9.1.7 IS 616: 2010, Clause. 9.1.7	1 N to 250 N 1 s to 600 s Qualitative
		Surge Test	EN/IEC 60065: 2005, Clause. 10.1 IS 616: 2010, Clause. 10.1	1 kV to 10 kV peak Qualitative
		Humidity treatment	EN/IEC 60065: 2005, Clause. 10.2 IS 616: 2010, Clause. 10.2	28 °C to 50 °C 90 % to 95 % RH Qualitative

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	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Insulation resistance	EN/IEC 60065: 2005, Clause. 10.3	1 V to 500 VDC
			IS 616: 2010, Clause. 10.3	1 s to 600 s
				0.05 MΩ to 2000 MΩ
		Dielectric strength	EN/IEC 60065: 2005, Clause. 10.3	1 V to 10 kV AC/DC
			IS 616: 2010, Clause. 10.3	1 s to 900 s Qualitative
			Fault conditions Tests	EN/IEC 60065: 2005, Clause. 11 IS 616: 2010, Clause. 11
	Mechanical strength – Bump	EN/IEC 60065: 2005, Clause. 12.1.1 IS 616: 2010, Clause. 12.1.1	0.1 cm to 5 cm	
			Qualitative	
	Mechanical strength – Impact	EN/IEC 60065: 2005, Clause. 12.1.3 IS 616: 2010, Clause. 12.1.3	0.2 J to 1 J	
			0.1 m to 1 m Qualitative	

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	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Drop Test	EN/IEC 60065: 2005, Clause. 12.1.4 IS 616: 2010, Clause. 12.1.4	0.1 m to 1 m Qualitative
		Mechanical strength – Stress relief	EN/IEC 60065: 2005, Clause. 12.1.5 IS 616: 2010, Clause. 12.1.5	1 °C to 350 °C Qualitative
		Torque Test – Rod antenna	EN/IEC 60065: 2005, Clause. 12.6 IS 616: 2010, Clause. 12.6	1 N to 20 N 1 s to 600 s Qualitative
		Creepage and Clearance distances	EN/IEC 60065: 2005, Clause. 13 IS 616: 2010, Clause. 13	1 mm to 150 mm
		Determination of operating voltage	EN/IEC 60065: 2005, Clause. 13.2 IS 616: 2010, Clause. 13.2	1 V to 1000 V rms/VDC
		Component - Resistors	EN/IEC 60065: 2005, Clause. 14.1 IS 616: 2010, Clause. 14.1	40 (±)2 °C 90 % to 96 % RH 1 kV to 10 kV AC

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	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Provisions for protective resistance	EN/IEC 60065: 2005, Clause. 15.2 IS 616: 2010, Clause. 15.2	0.001 Ω to 0.3 Ω 5 s to 600 s 0.1 A to 60 A
		Strain relief Test	EN/IEC 60065: 2005, Clause. 16.5 IS 616: 2010, Clause. 16.5	1 N to 40 N 1 Nm to 25 Nm 1 s to 600 s Qualitative
		Torque Test on screw terminals	EN/IEC 60065: 2005, Clause. 17.1 IS 616: 2010, Clause. 17.1	1 mm to 6 mm 1 Nm to 2.5 Nm Qualitative
		Torque Test on covers	EN/IEC 60065: 2005, Clause. 17.7 IS 616: 2010, Clause. 17.7	1 N to 10 N 1 Nm to 2.5 Nm Qualitative
		Stability Test	EN/IEC 60065: 2005, Clause. 19.1 IS 616: 2010, Clause. 19.1	1 ° to 10 ° angle Qualitative

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	Power adaptor, Televisions, Optical Disc Players, Amplifier, Electronic Musical System	Vertical force stability	EN/IEC 60065: 2005, Clause. 19.2 IS 616: 2010, Clause. 19.2	1 cm to 75 cm 1 N to 100 N Qualitative
		Horizontal force stability	EN/IEC 60065: 2005, Clause. 19.3 IS 616: 2010, Clause. 19.3	1 N to 250 N 0.1 m to 3 m Qualitative
		Wall Or Ceiling Or Equipment Rack Mounting Test	EN/IEC 60065: 2005, Clause. 19.6 IS 616: 2010, Clause. 19.6	1 kg to 100 kg 1 s to 600 s Qualitative
		Resistance to Heat, Fire and Tracking (Glow wire Test)	EN/IEC 60065: 2005, Clause. 20, Annexure. G IS 616: 2010, Clause. 20, Annexure. G	Upto 850 °C Qualitative
		Resistance to Heat, Fire and Tracking (Needle flame)	EN/IEC 60065: 2005, Clause. 20, Annexure. G IS 616: 2010, Clause. 20, Annexure. G	1 min to 1 hr 2 mm, 12 mm 100 °C to 700 °C Qualitative
		Resistance to Heat, Fire and Tracking (Flame Test)	EN/IEC 60065: 2005, Clause. 20, Annexure. G	1 mm to 50 mm Qualitative

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Accreditation Standard **ISO/IEC 17025: 2005**

Discipline **Electronics Testing** **Issue Date** **05.08.2016**

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
3.	Secondary cells & Batteries			
a.	Lithium Ion cells & batteries, Ni-MH cells & batteries	Insulation and wiring	IS 16046: 2015 Rev 1 (Clause. 5.2)	5 MΩ at 500 VDC for 60 s
		Low-rate charging	IS 16046: 2015 Rev 1 (Clause. 7.2.1)	0.50 V to 60 V / 0.30 A to 25 A Qualitative
		Vibration	IS 16046: 2015 Rev 1 (Clause. 7.2.2)	10 Hz to 60 Hz/ 5 Hz to 2300 Hz Amplitude-1.6 mm (P-P)/50.8 mm(P-P) 0.19 g to 4.6 g Acceleration Qualitative
		Moulded case stress at high ambient temperature (Batteries)	IS 16046: 2015 Rev 1 (Clause. 7.2.3)	20 °C to 350 °C Qualitative
		Temperature cycling	IS 16046: 2015 Rev 1 (Clause. 7.2.4)	150 °C to (-)40 °C Qualitative
		External short circuit	IS 16046: 2015 Rev 1 (Clause. 7.3.2)	0.1 mΩ to 2000 Ω Qualitative

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Lithium Ion cells & batteries, Ni-MH cells & batteries	Free fall	IS 16046: 2015 Rev 1 (Clause. 7.3.3)	100 mm to 1000 mm Qualitative
		Mechanical shock(Crash hazard)	IS 16046: 2015 Rev 1 (Clause. 7.3.4)	1 g to 200 g, 5 Hz to 5000 Hz Qualitative
		Overcharge	IS 16046: 2015 Rev 1 (Clause. 7.3.8)	0.50 V to 60 V/ 0.30 A to 20A Qualitative
		Charging-2nd procedure	IS 16046: 2015 Rev 1 (Clause. 8.1.2)	0.50 V to 60 V/ 0.30 A to 20 A Qualitative
		Incorrect installation	IS 16046: 2015 Rev 1 (Clause. 7.3.1)	Resistor of 1 Ω Qualitative
		Thermal abuse(Cells)	IS 16046: 2015 Rev 1 (Clause. 7.3.5)	20 °C to 200 °C Qualitative
		Forced discharge(Cell)	IS 16046: 2015 Rev 1 (Clause. 7.3.9)	0.50 V to 60 V/ 0.30 A to 20 A Qualitative
		Transport Tests	UN38.3 (6 th Edition), 2015	

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Lithium Ion cells & batteries, Ni-MH cells & batteries	T1 : Altitude Simulation	UN 38.3 Clause. 4.1	10 mBar to 930 mBar Qualitative
		T2 : Thermal Test	UN 38.3 Clause. 4.2	150 °C to (-)40 °C Qualitative
		T3 : Vibration	UN 38.3 Clause. 4.3	5 Hz to 2300 Hz Amplitude 0.1 mm to 50.8 mm (P-P) Qualitative
		T4 : Shock	UN 38.3 Clause. 4.4	1 g to 200 g, 5 Hz to 5000 Hz Qualitative
		T5 : External Short Circuit	UN 38.3 Clause. 4.5	0.1 mΩ to 2000 Ω Qualitative
		T6 (a) : Impact & (Crush)	UN 38.3 Clause. 4.6	200 Nw to 18 kNw Qualitative
		T7 : Over Charge	UN 38.3 Clause. 4.7	0.50 V to 60 V/ 0.30 A to 20 A Qualitative
		T8 : Forced Discharge	UN 38.3 Clause. 4.8	0.50 V to 60 V/ 0.30 A to 20 A Qualitative

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